

ASSOCIATED ELECTRONICS RESEARCH FOUNDATION

An industrial visit was organized to Associated Electronics Research Foundation (AERF), Research & Development Centre at Noida on 16th September, 2014 for 15 students of IIIrd and 15 students of Vth Semester. The overall objective of the visit was to give students a practical exposure to different testing facilities available in AERF. Equipment like Beam Scanning Testing Jig, Coating Thickness Tester, Hardness Tester, Tensile Strength Tester, and Vibration Tester were demonstrated and explained practically to the students.



Students at the Industrial Visit